Special Issue

Novel Measurement Techniques and Their Applications in Industrial Engineering

Message from the Guest Editors

It has become apparent in recent years that the requirements and expectations of customers on the global market are growing bigger and bigger. Thus, it is necessary to manufacture products of a very high quality. Quality control of products requires the application of relevant measurement methods and instruments. Therefore, this Special Issue is dedicated to the problems of measurement and quality control in the area of manufacturing engineering. In particular, works concerning the following problems are invited: increasing the accuracy of coordinate measuring machines, surface measurements, measurements of form deviations, the application of 3D scanners in metrology, application of computed tomography in metrology, quality control methods, and uncertainty analysis. Manuscripts concerning novel manufacturing technologies are invited, too; however, their authors should demonstrate that the problems of measurement are predominant in their works.

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Deadline for manuscript submissions

closed (31 March 2024)

Applied Sciences

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CiteScore 5.5

mdpi.com/si/109964

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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